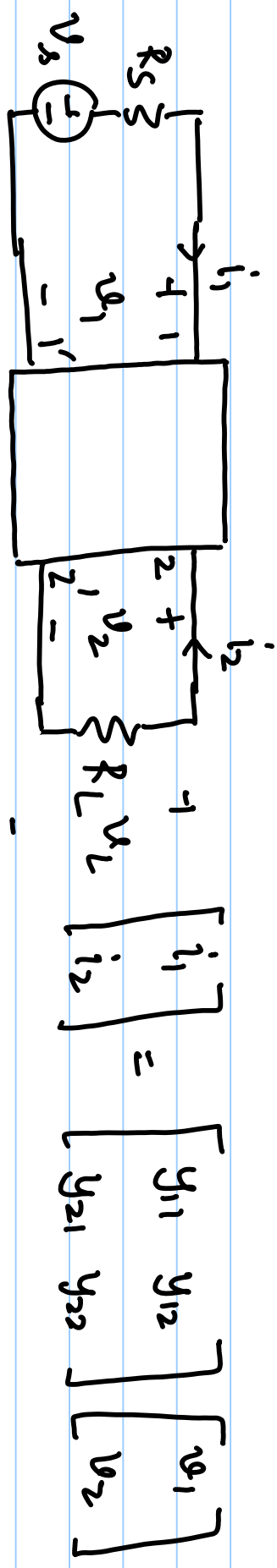


# lecture # 06



$$\frac{v_L}{v_s} = \frac{-y_{21}/R_s}{(y_{11} + \frac{1}{R_s})(y_{22} + \frac{1}{R_L}) - y_{12}y_{21}}$$

$(y_{11} + \frac{1}{R_s})(y_{22} + \frac{1}{R_L}) - y_{12}y_{21} \rightarrow 0 \rightarrow \infty$

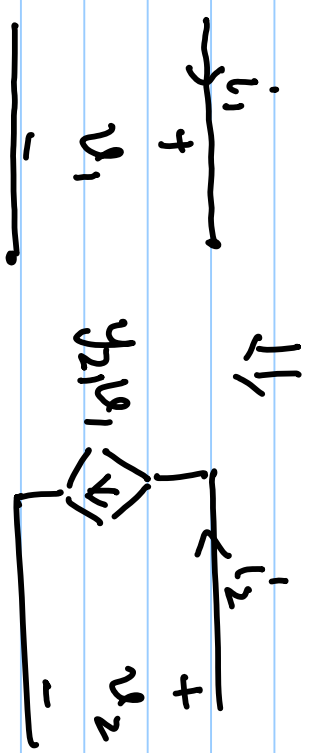
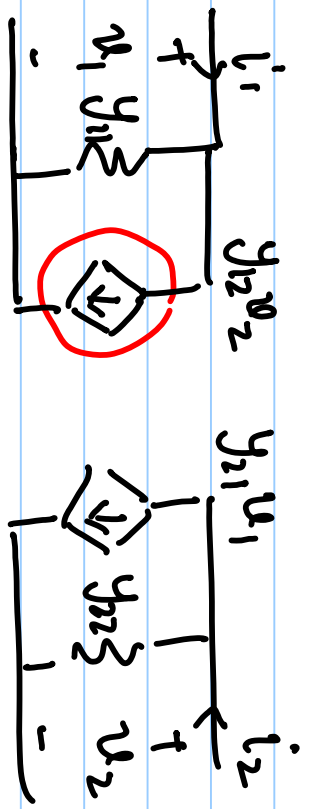
$y_{11} : 0$

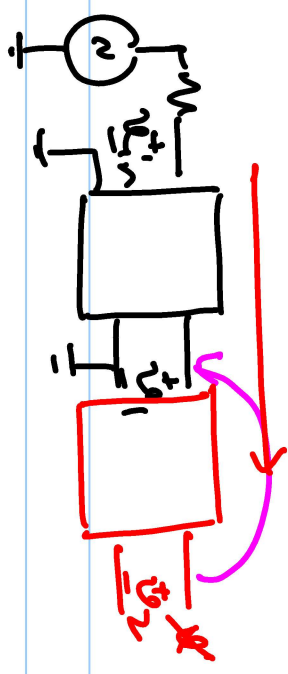
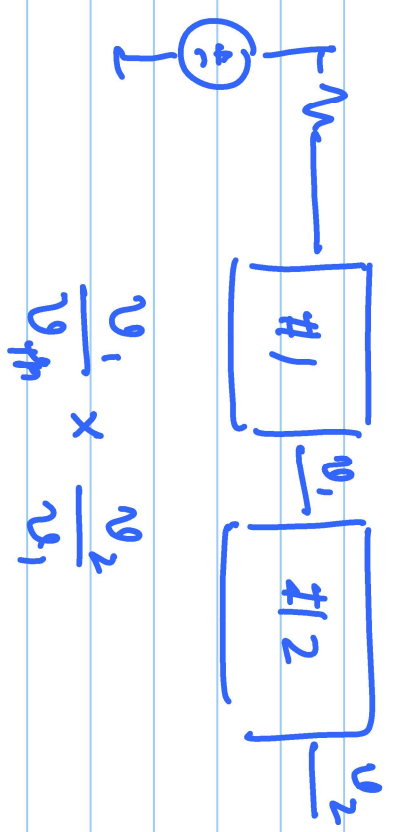
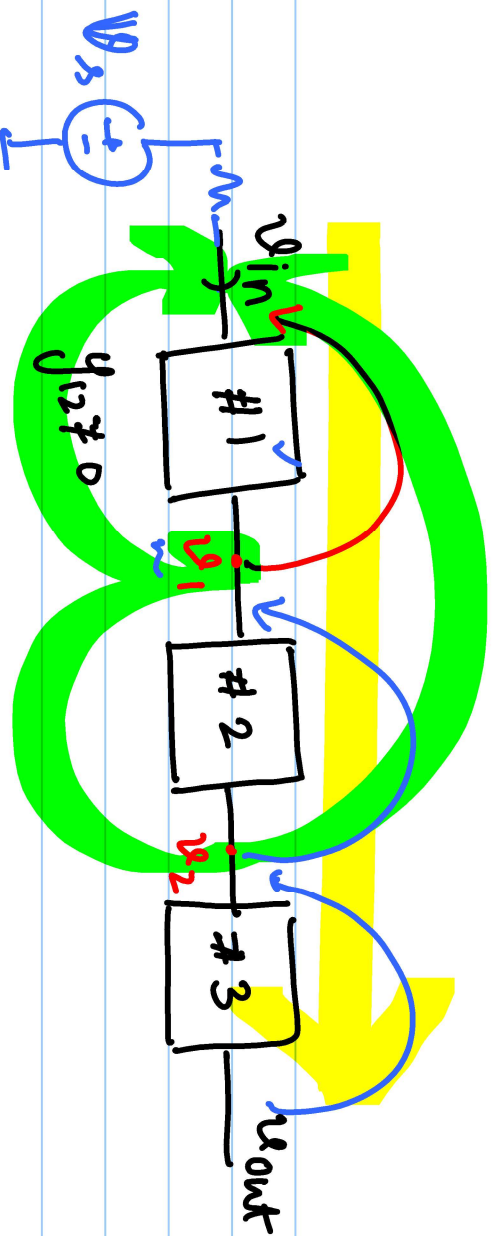
$y_{12} : 0$

$y_{22} : 0$

$y_{21} :$

$y_{21} \rightarrow y_{12}$





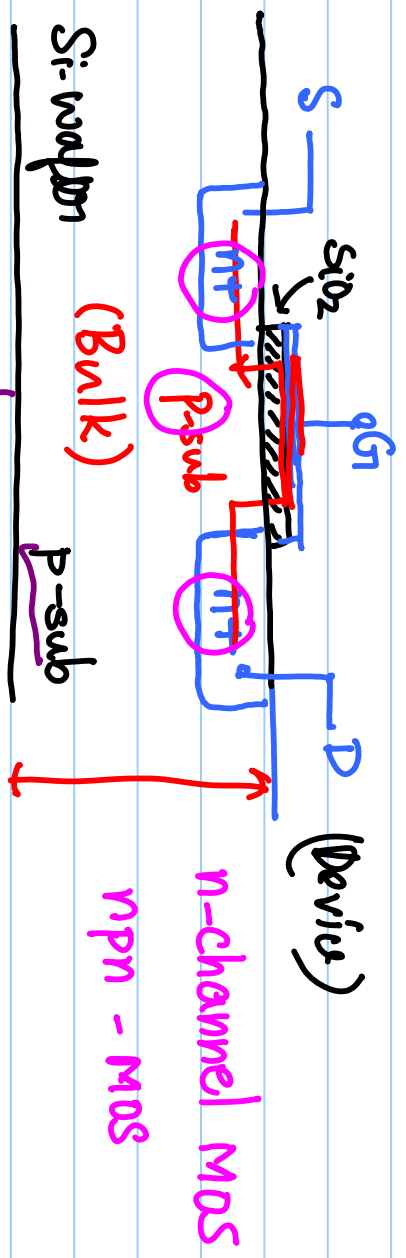
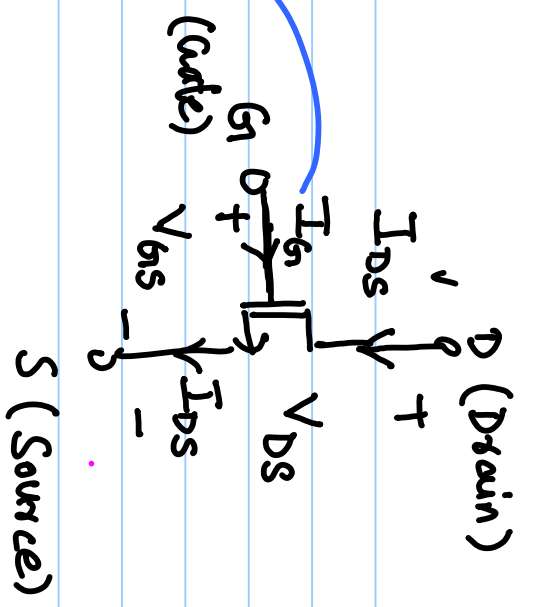
$$\frac{V_1}{V_2} = H(s) = A$$

$$\frac{V_2}{V_{in}} = A^2$$

Controlled  $y_2$  →  
 independ  $y_1$  →  
 entity.  $y_0$  →

$$\frac{2}{10} \rightarrow \frac{2}{5}$$

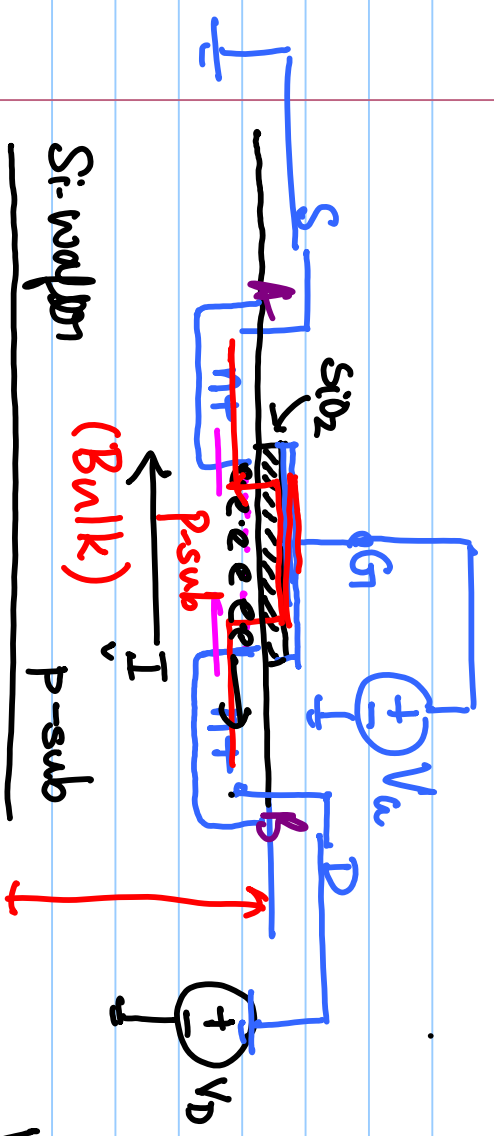
# MOSFET: Metal-Oxide-Semiconductor FET

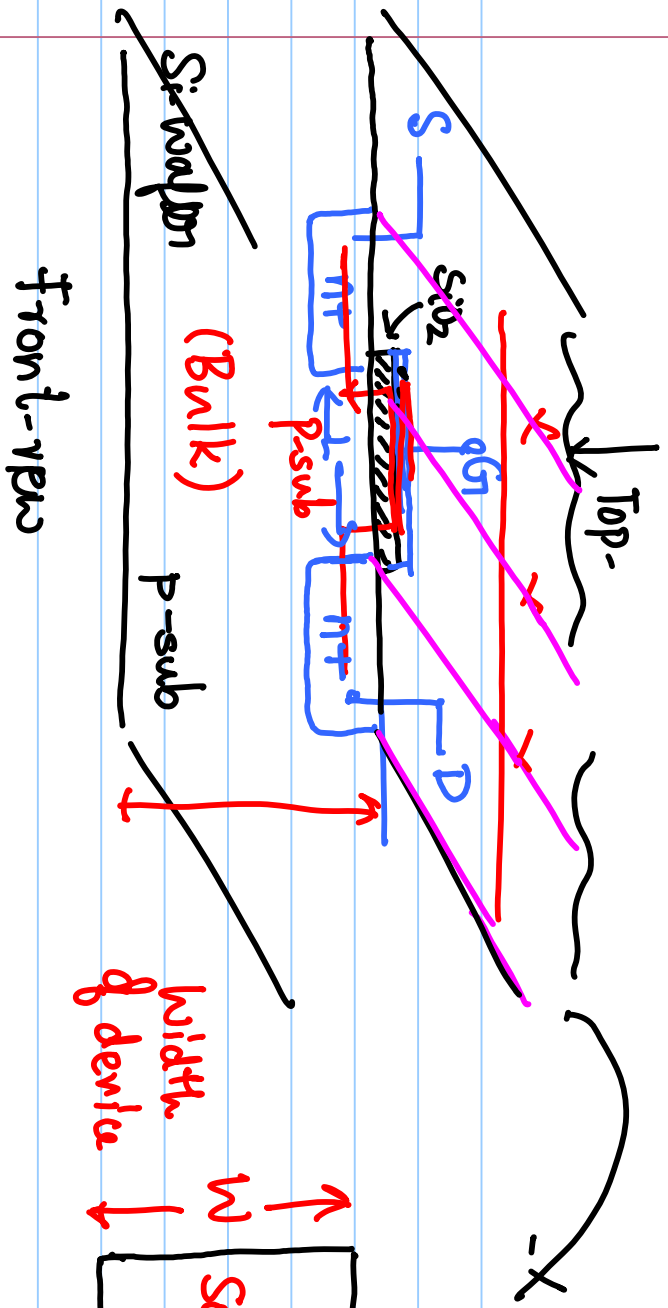


$\downarrow \epsilon$   
 $\text{SiO}_2$  (dielectric) }  $\Rightarrow$  Capacitor  
 p-sub

$V_D = V_S = 0$   
 Change  $V_G > 0$   
 $V_{GS} > V_{th}$

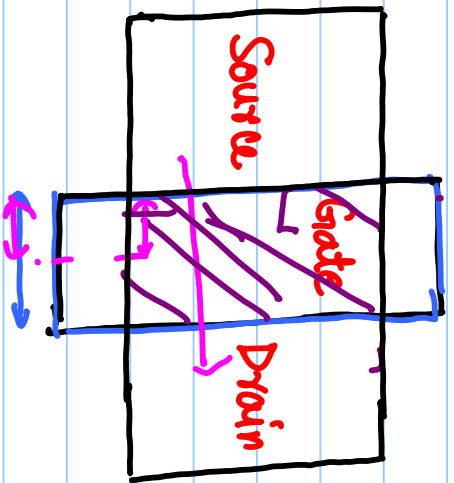
$i = \frac{dq}{dt}$



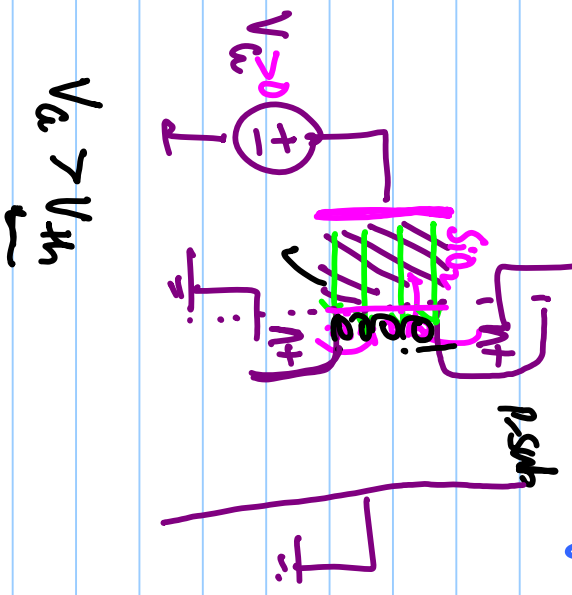
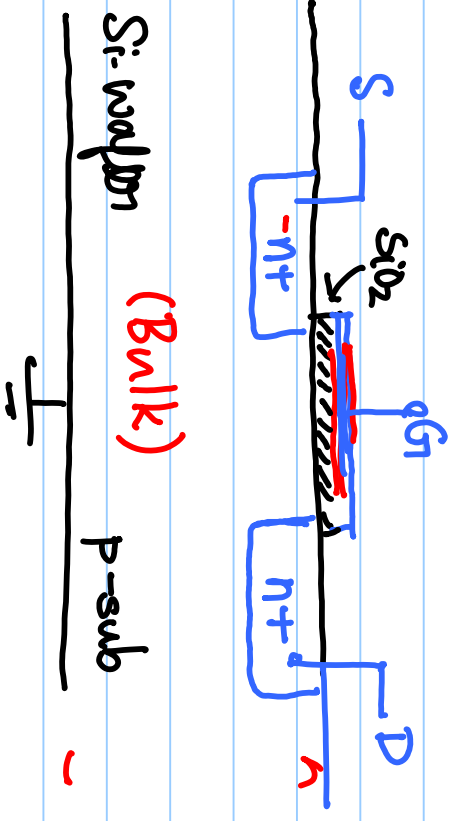


width of device

front-view

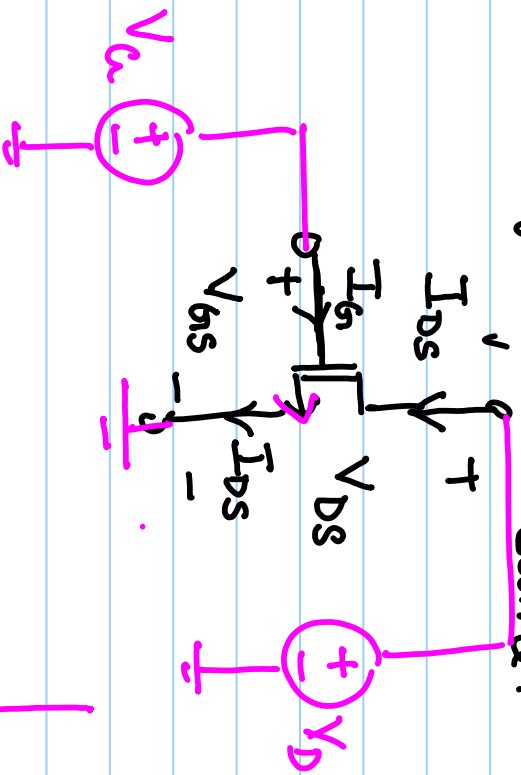


L: length of channel.



$V_G > V_{th}$

MOS: voltage controlled current source.



a) when  $V_{GS} \leq V_{th}$ ,  $V_{DS} \geq 0$

$V_{GS}$ : gate-to-source potential

$V_{th}$ : threshold voltage of device.

$$I_{DS} = 0, I_G = 0$$

b)  $V_{GS} > V_{th}$ ,  $V_{DS} < V_{GS} - V_{th}$

$V_{DS}$ : drain-to-source potential difference

$$I_G = 0$$

$$I_{DS} = \mu_n C_{ox} \frac{W}{L} \left[ (V_{GS} - V_{th}) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

$\mu_n$ : mobility of e.

$C_{ox}$ : capacitance per unit area.

$W$ : width of the device

$L$ : length of channel.

c)  $V_{GS} > V_{th}$ ,  $V_{DS} > V_{GS} - V_{th}$   
 $I_G = 0$

$$I_{DS} = \frac{\mu_n C_{ox} W}{2 L} (V_{GS} - V_{th})^2$$

